MOS

TMS 3126, 3127, 3128, 3129, 3130, 3132 NC DUAL 96-, 100-, 128-, 132-, 133-, 136-, 144-BIT STATIC SHIFT REGISTERS

OCTOBER 1977

- DC to 2.5-MHz Operation
- Static Configuration
- Single TTL-Compatible Clock
- Inputs and Outputs Fully TTL-Compatible
- Push-Pull Output Buffers
- On-Chip Recirculate Logic
- Power Supplies . . . 5 V, —12 V
- Seven Standard Bit Lengths

REC 1 0 0 8 Vss IN 1 2 0 0 7 IN 2 OUT 1 3 0 0 6 OUT 2 VGG 4 0 0 5 CLOCK

8-PIN DUAL-IN-LINE PACKAGE (TOP VIEW)

escription

This series is a family of MOS dual static shift registers. These circuits are monolithically constructed by use of thickoxide techniques and P-channel enhancement-type transistors, which allow TTL-compatibility for ease of system design.

An on-chip clock generator provides three internal phases from a single external TTL-level clock. All inputs including the low-capacitance clock can be driven directly from Series 74 TTL circuits without the need for pull up resistors. The push-pull outputs are compatible with Series 74 TTL and have a fan-out capability of one TTL load. A current limiter has been incorporated in the output buffers to reduce power dissipation when driving bipolar logic. No external components are needed for TTL interface.

Cross-coupled inverters (flip-flops) are employed to implement each bit storage location. This static design allows input data rates from dc to 2.5 MHz and long-term data storage. Recirculate logic has been incorporated on the chip to simplify system design.

These devices are offered in the 8-pin dual-in-line plastic package (suffix NC). The 8-pin dual-in-line package is designed for insertion in mounting-hole rows on 300-mil centers. These devices are characterized for operation from -25°C to

pplications

Various bit lengths are offered to cover most computer peripheral applications such as printers, buffer memories, and CRT refresh memories.

peration

Transfer of data into and out of the shift registers occurs on the low-to-high transition of the clock. Input data must be set up a minimum time before the low-to-high clock transition and must be held for a minimum time after that transition. For long-term data storage, the clock must be maintained high, and in this mode the recirculate and data input levels may change without affecting the data output levels.

Recirculate occurs on the low-to-high clock transition with the recirculate control low. The recirculate control must be set up a minimum time before this transition and held a minimum time after the transition. Data is entered with the recirculate control high. During recirculation, data is continuously available at the output and the data input is inhibited.

SHIFT REGISTEE

TEXAS INSTRUMENTS

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functional block diagram OUT 1 PULL Φ2 CLOCK GENERATOR CLOCK φ2 φ3 PUSH-PULL BUFFER OUT 2 N BIT REGISTER REC

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)*

Supply voltage, VGG (see Note 1)															-20 V to 0.3 V
Clock input voltage (see Note 1)	•		•	•	•	•	•		Ċ						-20 V to 0.3 V
Data input voltage (see Note 1)	•		•	•		Ċ									-20 V (0 0.5 V
															-25 C 10 05 C
Operating free-air temperature range Storage temperature range	•	·	Ċ	Ċ			Ċ								55°C to 150°C
Storage temberature range	•	•		-	-					 	 : -	 	 	f	hetrate). Throughout

NOTE 1: Under absolute maximum ratings, voltage values are with respect to the normally most-positive supply, VSS (substrate). Throughout

NOTE 1: Under absolute maximum ratings, voltage values are with respect to the normally most-positive supply, V_{SS} (substrate). Throughout the remainder of this data sheet voltage values are with respect to a floating ground.

*Comment: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the "Recommended Operating Conditions" section of this specification is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device rationally like. device reliability.

recommended operating conditions

	MIN	NOM	MAX	UNIT
PARAMETER	-11	-12	-13	V_
Supply voltage, VGG	4.5	- 5	5.5	v
Supply voltage, VSS	V _{SS} -1.8			V
High-level input voltage, V _I H	VSS -1.8	v	ss -3.9	† v
Low-level input voltage, VIL		0.02	5	μ. μ.
Clock pulse transition time, low-to-high level, tŢLH(φ)		0.02	- 5	115
Clock pulse transition time, high-to-low level, t _{THL} (φ)	300	0.02		ns
Pulse width, clock high, tw(pH)	100		1000000	ns
Pulse width, clock low, tw(oL)				ns.
Recirculate pulse width, tw(rec)	125			ns
Data setup time, t _{su(da)}				ns
Recirculate setup time, t _{sufrec})	100			ns.
Data hold time, th(da)	80			ns
Recirculate hold time, th(rec)	25		2.5	MH
Clock frequency, fo	0		85	c
Operating free-air temperature, TA	-25			

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electrical characteristics under nominal operating conditions, $T_A = -25^{\circ}$ C to 85° C (unless otherwise noted)

			MIN	TYPT	MAX	UNIT
	PARAMETER	TEST CONDITIONS				
-	High-level output voltage	IOH = 0.2 mA			0.4	V
VOH_ VOL	Low-level output voltage	I _{OL} = 1.6 mA			-500	nA.
VOL.	input current (all inputs)	V _I = 0.8 V		-22	-30	mA
IGG	Supply current from VGG	TA = 25°C, f = 1 MHz		374	510	mW
PD	Power dissipation					pF
	input capacitance, all inputs	V1 = 5 V. f = 1 MHz	1	3.5	5	
Ci	except clock	Value 5 V f = 1 MHz		3.5	5	pF
	of it leaves conscitance	V _{1(φ)} = 5 V, f = 1 MHz	L			

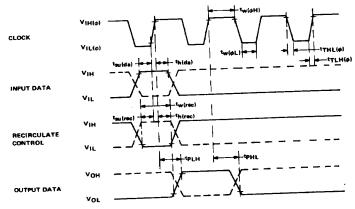
'All typical values are at TA = 25°C.

witching characteristics under nominal operating conditions, $T_A = -25^{\circ}\text{C}$ to 85°C

•			MIN	MAX	UNIT	1
1	PARAMETER	TEST CONDITIONS	MIN			1
	Propagation dalay time, low-to-high-	Load = 1 TTL gate (see Note 2)		250	ns.	١
	tPLH level output from clock			250	ns.	1
	Propagation delay time, high-to-low-			250		J
	tout					

NOTE 2: For test purposes, a TTL load is simulated by a load of 2.7 $k\Omega$ and 20 pF between the output and VSS

voltage waveforms



NOTE: All timing measurements are made at 10% or 90% points.

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